

<b>Notice of References Cited</b>	Application/Control No. 09/884,925	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner John M. Villecco	Art Unit 2612	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0141069	07-2004	Nakami, Yoshihiro	348/231.6
	B	US-6,856,760	02-2005	Takahashi et al.	348/231.3
	C	US-6,829,624	12-2004	Yoshida, Masanori	348/231.4
	D	US-6,738,092	05-2004	Nakagawa et al.	348/231.3
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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